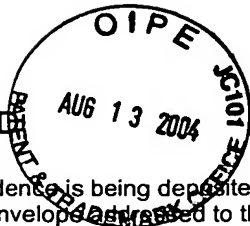


Docket No.: PEK-In1163



I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

By: W. Wilson

Date: August 10, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/751,316 Confirmation No: 1985
Applicant : Wilhelm Asam et al.
Filed : January 2, 2004
Title : Method for Detecting the Reliability of Integrated Semiconductor Components at High Temperatures
Art Unit : 2826
Examiner : Scott R. Wilson

Docket No. : PEK-In1163 D
Customer No. : 24131

Letter under 37 C.F.R. §1.312

Hon. Commissioner for Patents

Sir:

In the IDS filed on January 2, 2004 German Patent DE 198 41 202 C1 (Gärtner et al.), dated March 2, 2000 was cited. The patent had been originally submitted in an IDS in parent application 10/200,934 on August 16, 2002. Inadvertently, this German patent was not listed on Form PTO-1449.

Applicants are submitting herewith a copy of German Patent DE 198 41 202 C1, corresponding U.S. Patent No. 6,255,892 B1 and Form PTO-1449.

Applicants kindly request that the Examiner consider this reference.

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'W. Stemer', written over a horizontal line.

For Applicants

WERNER H. STEMER
REG. NO. 34,956

Date: August 10, 2004

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/bmb

FORM PTO-1449 (SUBSTITUTE)	Attorney Docket No.: PEK-In1163 D	Applic. No. 10/751,316
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Applicant Wilhelm Asam et al.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Filing Date January 2, 2004	Group Art Unit 2826

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	6,255,892 B1	07/03/01	Gärtner et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J	198 41 202 C1	03/02/00	Germany			
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	
	P	
EXAMINER	DATE CONSIDERED	

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.